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October 2014

FDPC8011S

PowerTrench® Power Clip 25V Asymmetric Dual N-Channel MOSFET

Features

Q1: N-Channel

■ Max $r_{DS(on)}$ = 7.3 m Ω at V_{GS} = 4.5 V, I_D = 12 A

Q2: N-Channel

- Max $r_{DS(on)} = 2.1 \text{ m}\Omega$ at $V_{GS} = 4.5 \text{ V}$, $I_D = 24 \text{ A}$
- Low inductance packaging shortens rise/fall times, resulting in lower switching losses
- MOSFET integration enables optimum layout for lower circuit inductance and reduced switch node ringing
- RoHS Compliant

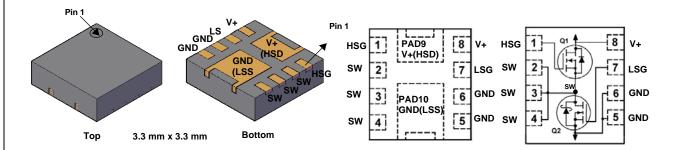


General Description

This device includes two specialized N-Channel MOSFETs in a dual package. The switch node has been internally connected to enable easy placement and routing of synchronous buck converters. The control MOSFET (Q1) and synchronous SyncFETTM (Q2) have been designed to provide optimal power efficiency.

Applications

- Computing
- Communications
- General Purpose Point of Load



MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Parameter	Q1	Q2	Units
V_{DS}	Drain to Source Voltage	25	25	V
V_{GS}	Gate to Source Voltage	12	12	V
	Drain Current -Continuous (Package limited) T _C = 25	°C 20	60	
I_D	-Continuous T _A = 25	°C 13 ^{1a}	27 ^{1b}	Α
	-Pulsed	40	120	
E _{AS}	Single Pulse Avalanche Energy (Note	3) 21	97	mJ
D	Power Dissipation for Single Operation $T_A = 25$	°C 1.6 ^{1a}	2.0 ^{1b}	W
P_{D}	Power Dissipation for Single Operation $T_A = 25 ^{\circ}\text{C}$		0.9 ^{1d}	VV
T _J , T _{STG}	Operating and Storage Junction Temperature Range	-55 t	o +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	77 ^{1a}	63 ^{1b}	
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	151 ^{1c}	135 ^{1d}	°C/W
$R_{\theta JC}$	Thermal Resistance, Junction to Case	5.0	3.5	

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
13OD/15OD	FDPC8011S	Power Clip 33	13 "	12 mm	3000 units

Electrical Characteristics $T_J = 25$ °C unless otherwise noted

Symbol	Parameter	Test Conditions	Туре	Min	Тур	Max	Units
Off Chara	ncteristics						
D\/	Drain to Course Breakdown Valtage	$I_D = 250 \mu A, V_{GS} = 0 V$	Q1	25			V
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 1 \text{ mA}, V_{GS} = 0 \text{ V}$	Q2	25			V
ΔBV_{DSS}	Breakdown Voltage Temperature	I _D = 250 μA, referenced to 25 °C	Q1		14		mV/°C
ΔT_{J}	Coefficient	I _D = 10 mA, referenced to 25 °C	Q2		24		IIIV/ C
	Zara Cata Valtaga Drain Current	V _{DS} = 20 V, V _{GS} = 0 V	Q1			1	μΑ
IDSS	Zero Gate Voltage Drain Current	V _{DS} = 20 V, V _{GS} = 0 V	Q2			500	μΑ
	Gate to Source Leakage Current,	V _{GS} = 12 V/-8 V, V _{DS} = 0 V	Q1			±100	nA
IGSS	Forward	$V_{GS} = 12 \text{ V/-8 V}, V_{DS} = 0 \text{ V}$	Q2			±100	nA

On Characteristics

V _{GS(th)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$ $V_{GS} = V_{DS}, I_D = 1 mA$	Q1 Q2	0.8 1.1	1.2 1.4	2.2 2.2	٧
۸۷	Gate to Source Threshold Voltage	$I_D = 250 \mu A$, referenced to 25 °C	Q1		-4	2.2	
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Temperature Coefficient	$I_D = 10$ mA, referenced to 25 °C	Q2		-3		mV/°C
		$V_{GS} = 10 \text{ V}, I_D = 13 \text{ A}$			4.6	6.0	
		$V_{GS} = 4.5 \text{ V}, I_D = 12 \text{ A}$	Q1		5.4	7.3	
_	Drain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 13 \text{ A}, T_J = 125 \text{ °C}$			5.6	7.3	mΩ
r _{DS(on)}	Diain to Source On Resistance	$V_{GS} = 10 \text{ V}, I_D = 27 \text{ A}$			1.2	1.8	1112.2
		$V_{GS} = 4.5 \text{ V}, I_D = 24 \text{ A}$	Q2		1.4	2.1	
		$V_{GS} = 10 \text{ V}, I_D = 27 \text{ A}, T_J = 125 ^{\circ}\text{C}$			1.7	2.4	
a	Forward Transconductance	$V_{DS} = 5 \text{ V}, I_{D} = 13 \text{ A}$	Q1		97		S
g _{FS} Forward Transconductance		$V_{DS} = 5 \text{ V}, I_{D} = 27 \text{ A}$	Q2		231		3

Dynamic Characteristics

-					
C _{iss}	Input Capacitance	Q1: V _{DS} = 13 V, V _{GS} = 0 V, f = 1 MHZ	Q1 Q2	1240 4335	pF
C _{oss}	Output Capacitance	Q2:	Q1 Q2	332 1126	pF
C _{rss}	Reverse Transfer Capacitance	$V_{DS} = 13 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHZ}$	Q1 Q2	49 143	pF
R _g	Gate Resistance		Q1 Q2	0.4 0.5	Ω

Switching Characteristics

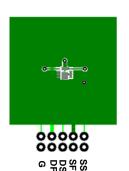
t _{d(on)}	Turn-On Delay Time			Q1 Q2	7 13	ns
t _r	Rise Time		Q1: $V_{DD} = 13 \text{ V}, I_{D} = 13 \text{ A}, R_{GEN} = 6 \Omega$ Q2: $V_{DD} = 13 \text{ V}, I_{D} = 27 \text{ A}, R_{GEN} = 6 \Omega$		2 5	ns
t _{d(off)}	Turn-Off Delay Time				20 38	ns
t _f	Fall Time	VDD = 13 V, 1D = 21			2 4	ns
Qg	Total Gate Charge	V _{GS} = 0 V to 10 V		Q1 Q2	19 64	nC
Qg	Total Gate Charge	V _{GS} = 0 V to 4.5 V	$V_{GS} = 0 \text{ V to } 4.5 \text{ V}$ $I_{D} = 13 \text{ V},$ $I_{D} = 13 \text{ A}$		9 30	nC
Q _{gs}	Gate to Source Gate Charge		Q2 V _{DD} = 13 V,	Q1 Q2	2.6 9.3	nC
Q _{gd}	Gate to Drain "Miller" Charge		$V_{DD} = 13 \text{ V},$ $I_{D} = 27 \text{ A}$		2.3 7.7	nC

Electrical Characteristics T_J = 25 °C unless otherwise noted

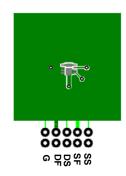
Symbol	Parameter	Test Conditions	Туре	Min	Тур	Max	Units	
Drain-Sou	Orain-Source Diode Characteristics							
V_{SD}	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 13 \text{ A}$ (Note 2) $V_{GS} = 0 \text{ V}, I_S = 27 \text{ A}$ (Note 2)	Q1 Q2		0.8 0.8	1.2 1.2	V	
t _{rr}	Reverse Recovery Time	Q1 I _F = 13 A, di/dt = 100 A/μs	Q1 Q2		22 30		ns	
Q _{rr}	Reverse Recovery Charge	Q2 $I_F = 27 \text{ A}, \text{ di/dt} = 300 \text{ A/}\mu\text{s}$	Q1 Q2		8 32		nC	

Notes

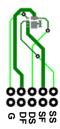
 $1.R_{\theta,JA}$ is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. $R_{\theta,JC}$ is guaranteed by design while $R_{\theta,CA}$ is determined by the user's board design.



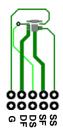
a. 77 °C/W when mounted on a 1 in² pad of 2 oz copper



b. 63 °C/W when mounted on a 1 in² pad of 2 oz copper



c. 151 °C/W when mounted on a minimum pad of 2 oz copper



d. 135 °C/W when mounted on a minimum pad of 2 oz copper

- 2 Pulse Test: Pulse Width < 300 $\mu s,$ Duty cycle < 2.0%.
- 3. Q1 :EAS of 21 mJ is based on starting $T_J = 25$ °C; N-ch: L = 1.2 mH, $I_{AS} = 6$ A, $V_{DD} = 23$ V, $V_{GS} = 10$ V. 100% test at L= 0.1 mH, $I_{AS} = 14.5$ A. Q2: EAS of 97 mJ is based on starting $T_J = 25$ °C; N-ch: L = 0.6 mH, $I_{AS} = 18$ A, $V_{DD} = 23$ V, $V_{GS} = 10$ V. 100% test at L= 0.1 mH, $I_{AS} = 32.9$ A.

Typical Characteristics (Q1 N-Channel) T_J = 25 °C unless otherwise noted

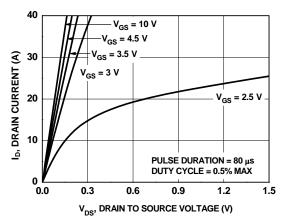


Figure 1. On Region Characteristics

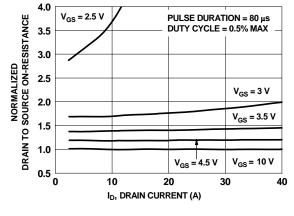


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

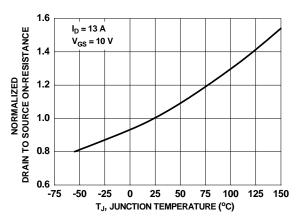


Figure 3. Normalized On Resistance vs Junction Temperature

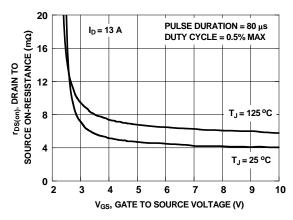


Figure 4. On-Resistance vs Gate to Source Voltage

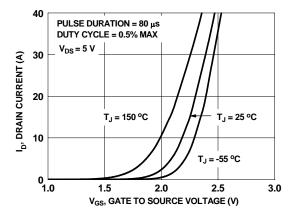


Figure 5. Transfer Characteristics

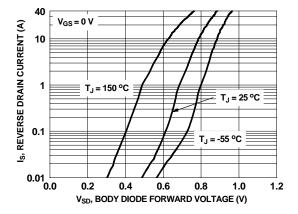


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics (Q1 N-Channel) T_J = 25 °C unless otherwise noted

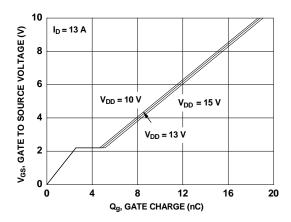


Figure 7. Gate Charge Characteristics

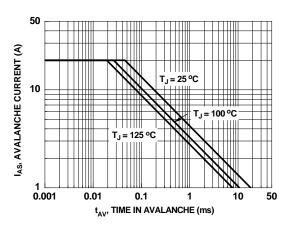


Figure 9. Unclamped Inductive Switching Capability

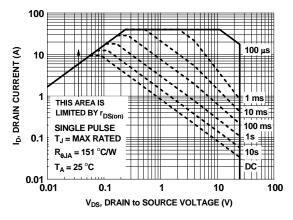


Figure 11. Forward Bias Safe Operating Area

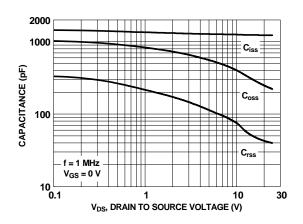


Figure 8. Capacitance vs Drain to Source Voltage

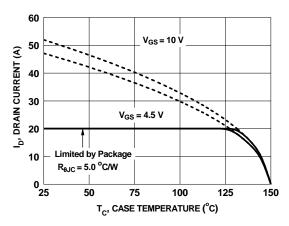


Figure 10. Maximum Continuous Drain Current vs. Ambient Temperature

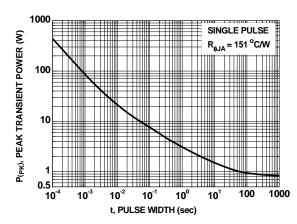


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics (Q1 N-Channel) T_J = 25 °C unless otherwise noted

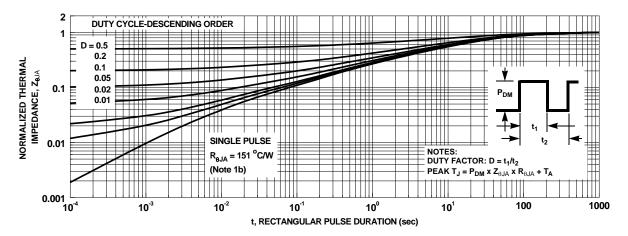


Figure 13. Junction-to-Ambient Transient Thermal Response Curve

Typical Characteristics (Q2 N-Channel) T_J = 25 °C unlenss otherwise noted

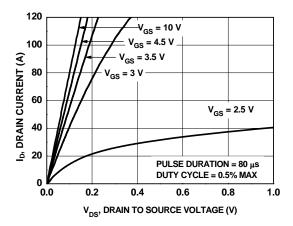


Figure 14. On-Region Characteristics

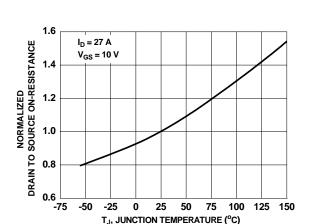


Figure 16. Normalized On-Resistance vs Junction Temperature

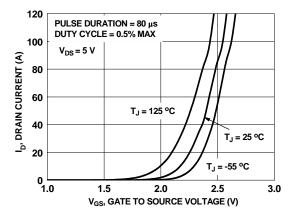


Figure 18. Transfer Characteristics

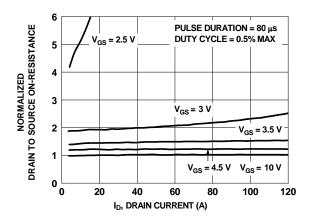


Figure 15. Normalized on-Resistance vs Drain Current and Gate Voltage

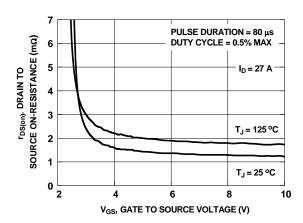


Figure 17. On-Resistance vs Gate to Source Voltage

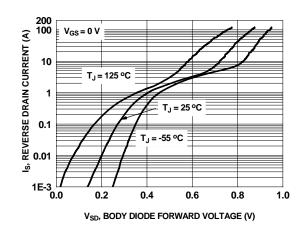


Figure 19. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics (Q2 N-Channel) T_J = 25 °C unlenss otherwise noted

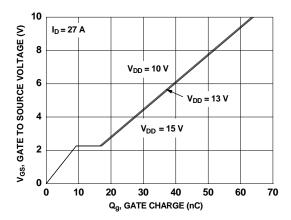


Figure 20. Gate Charge Characteristics

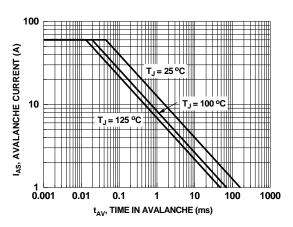


Figure 22. Unclamped Inductive Switching Capability

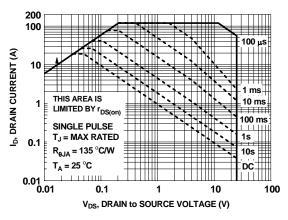


Figure 24. Forward Bias Safe Operating Area

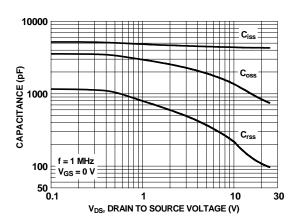


Figure 21. Capacitance vs Drain to Source Voltage

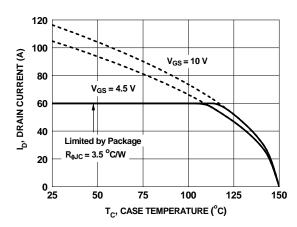


Figure 23. Maximum Continouns Drain Current vs Ambient Temperature

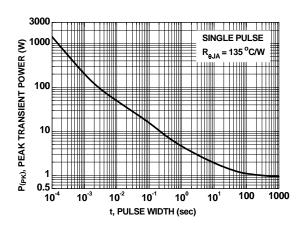


Figure 25. Single Pulse Maximum Power Dissipation

Typical Characteristics (Q2 N-Channel) $T_J = 25$ °C unlenss otherwise noted

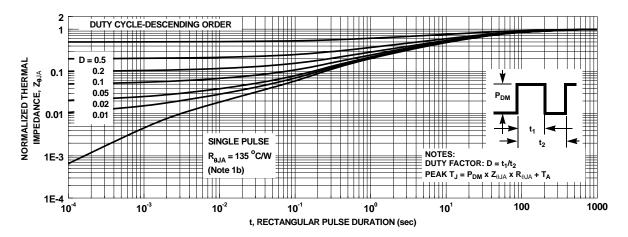


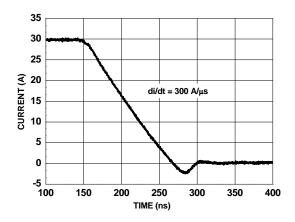
Figure 26. Junction-to-Ambient Transient Thermal Response Curve

Typical Characteristics (continued)

SyncFETTM Schottky body diode Characteristics

Fairchild's SyncFETTM process embeds a Schottky diode in parallel with PowerTrench MOSFET. This diode exhibits similar characteristics to a discrete external Schottky diode in parallel with a MOSFET. Figure 27 shows the reverse recovery characteristic of the FDPC8011S.

Schottky barrier diodes exhibit significant leakage at high temperature and high reverse voltage. This will increase the power in the device.



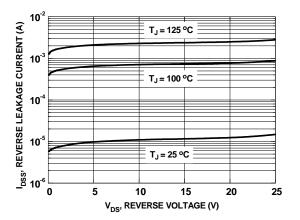


Figure 27. FDPC8011S SyncFETTM body diode reverse recovery characteristic

Figure 28. SyncFETTM body diode reverse leakage versus drain-source voltage

Application Information

Typical Application Diagram (Synchronous Rectifier Buck Converter)

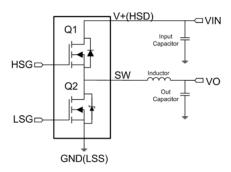


Figure 1.Power Clip in Buck Converter Topology

As shown in Figure 1, in the Power Clip package Q1 is the High Side MOSFET (Control MOSFET) and Q2 is the Low Side MOSFET (Synchronous MOSFET). Figure 2 below shows the package pin out. The blue overlay on the drawing indicates a typical PCB land pattern for the part.

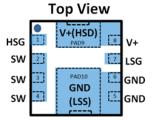


Figure 2.Top View of Power Clip

Table 1 Pin Information shows the name and description of each pin.

	PIN	Description
Number	Name	Description
1	HSG	Gate signal input of Q1 Gate
2,3,4	SW	Switch or Phase node, Source of Q1 and Drain of Q2
5,6,PAD 10	GND,GND(LSS) PAD	Ground, Source of Q2
7	LSG	Gate signal input of Q2 Gate
8,PAD 9	V+, V+(HSD) PAD	Input voltage of SR Buck converter, Drain of Q1

Table 1. Pin Information

Recommended PCB Layout Guidelines

As a PCB designer, it is necessary to address critical issues in layout to minimize losses and optimize the performance of the power train. Power Clip is a high power density solution and all high current flow paths, such as V+(HSD), SW and GND(LSS) should be short and wide for minimal resistance and inductance. V+(HSD) and GND(LSS) are the primary heat flow paths for the Power Clip. A recommended layout procedure is discussed below to maximize the electrical and thermal performance of the part.

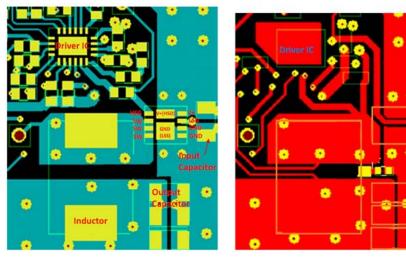


Figure 3.Top/Component (green) View and Bottom (red) PCB View

Following is a guideline, not a requirement which the PCB designer should consider.

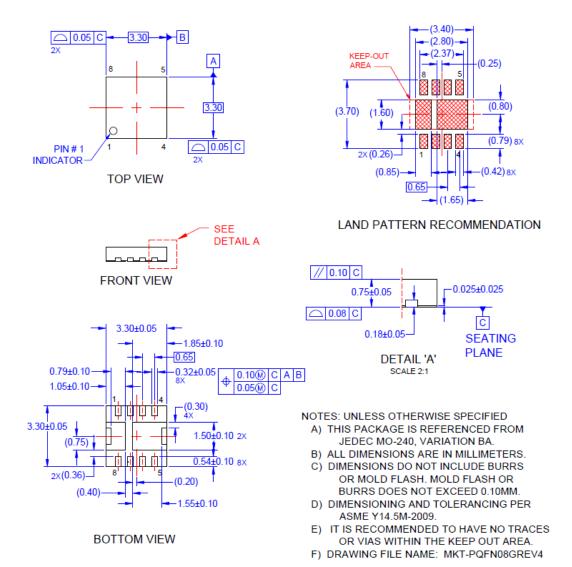
Figure 3 shows an example of a well designed layout. The discussion that follows summarizes the key features of this layout.

- "The input ceramic bypass capacitor between VIN and GND should be placed as close as possible to the pins V+ / V+(HSD) PAD and GND / GND(LSS) PAD to help reduce parasitic inductance and high frequency ringing. Several capacitors may be placed in parallel, and capacitors may be placed on both the top and bottom side of the board. The capacitor located immediately adjacent to the Power Clip will be the most effective at reducing HF parasitic. Caps located farther away, or on the opposite side of the board will also assist, but will be less effective due to increased trace inductance.
- "The Power Clip package design, with very short distance between pins V+ and GND, allows for a short connect distance to the input cap. This is a factor that enables the Power Clip switch loop to have very low parasitic inductance.
- "Use large copper areas on the component side to connect the V+ pin and V+ (HSD) pad, and the GND and GND(LSS) PAD.
- "The SW to inductor copper trace is a high current path. It will also be a high noise region due to switching voltage transients. The trace should be short and wide to enable a low resistance path and to minimize the size of the noise region. Care should be taken to minimize coupling of this trace to adjacent traces. The layout in Figure 3 shows a good example of this short, wide path.
- "The Power Trench® Technology MOSFETs used in the Power Clip are effective at minimizing SW node ringing. They incorporate a proprietary design¹ that minimizes the peak overshoot ring voltage on the switch node (SW). They allow the part to operate well within the breakdown voltage limits. For most layouts, this eliminates the need to add an external snubber circuit. If the designer chooses to use an RC snubber, it should be placed close to the part between the SW pins and GND / GND (LSS) PAD to dampen the high frequency ringing.
- "The Driver IC should be placed relatively closed to HSG pin and LSG pin to minimize G drive trace inductance. Excessive G trace length may slow the switching speed of the HS drive. And it may lead to excessive ringing on the LS G. If the designer must place the driver a significant distance away from the Power Clip, it would be a good practice to include a 0 Ohm resistor in the LS G path as a place holder. In the final design, if the LS G exhibits excessive LF ringing, efficiency can often be improved by changing this resistor to a few Ohms to dampen the LS G LF ringing.
- "The Power Clip has very good Junction-PCB heat transfer from all power pins. It has much better heat transfer Junction-GND (LSS) than traditional dual FET packages. In most cases, board ground will be the most effective heat transfer path on the PCB. Use a large copper area between GND / GND(LSS)PAD pins and board ground. To ensure the best thermal and electrical connection to ground, we recommend using multiple vias to interconnect ground plane layers as shown in Figure 3.

^{1.}Patent Pending

'Avoid using nar	row thermal relief trac	es on the V+/V+(I	HSD) PAD and GN	D / GND(LSS)PAD	pins. These will increa	se HF switch
loop inductance.	And these will increa	se ringing of the H	IF power loop and	the SW node.		

Dimensional Outline and Pad Layout





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 GreenBridge™

 Build it Now™
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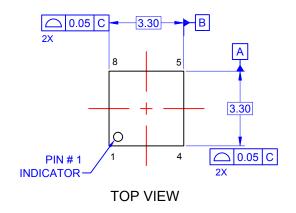
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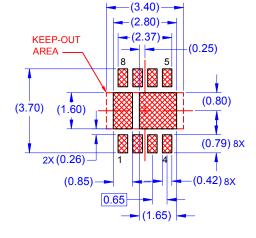
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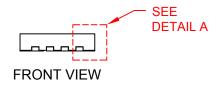
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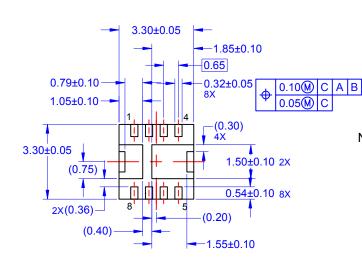
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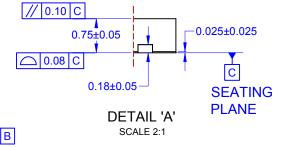












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